

CE EMC TEST REPORT

REPORT NO.: CE130610D13

MODEL NO.: P403 – *multiple listing see item 3.1*

RECEIVED: Jun. 10, 2013

TESTED: Jun. 11 ~ 19, 2013

ISSUED: Jun. 19, 2013

APPLICANT: TOP VICTORY ELECTRONICS (TAIWAN) CO., LTD.

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RELEASE CONTROL RECORD

ISSUE NO.	REASON FOR CHANGE	DATE ISSUED
CE130610D13	Original release	Jun. 19, 2013



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1 CERTIFICATION

PRODUCT: LCD Monitor

BRAND NAME: NEC

MODEL NO.: P403 – *multiple listing see item 3.1*

APPLICANT: TOP VICTORY ELECTRONICS (TAIWAN) CO., LTD.

TEST SAMPLE: ENGINEERING SAMPLE

TESTED: Jun. 11 ~ 19, 2013

STANDARDS: EN 55022:2010, Class B

CISPR 22:2008, Class B

AS/NZS CISPR 22:2009 +A1:2010, Class B

EN 61000-3-2:2006 +A1:2009 +A2:2009, Class D

EN 61000-3-3:2008

EN 55024:2010

IEC 61000-4-2:2008 ED.2.0

IEC 61000-4-3:2010 ED.3.2

IEC 61000-4-4:2012 ED.3.0

IEC 61000-4-5:2005 ED.2.0

IEC 61000-4-6:2008 ED.3.0

IEC 61000-4-8:2009 ED.2.0

IEC 61000-4-11:2004 ED.2.0

The above equipment (model no.: P403) has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

PREPARED BY : Sandra Lin, **DATE:** Jun. 19, 2013
(Sandra Lin / Specialist)

APPROVED BY : Kenny Meng, **DATE:** Jun. 19, 2013
(Kenny Meng / Assistant Manager)

2 SUMMARY OF TEST RESULTS

The EUT has been tested according to the following specifications:

EMISSION			
Standard	Test Type	Result	Remarks
EN 55022:2010, Class B CISPR 22:2008, Class B AS/NZS CISPR 22:2009 +A1:2010, Class B	Conducted Test	PASS	Meets Class B Limit Minimum passing margin is -3.81 dB at 0.38 51 MHz
	Conducted Test (Telecom port)	N/A	EUT has no telecom port.
	Radiated Test (30MHz ~ 6GHz)	PASS	Meets Class B Limit Minimum passing margin is -4.17 dB at 108.31 MHz
EN 61000-3-2:2006 +A1:2009+A2:2009, Class D	Harmonic current emissions	PASS	Meets Class D Limit
EN 61000-3-3:2008	Voltage fluctuations & flicker	PASS	Meets the requirements.

IMMUNITY (EN 55024:2010)			
Standard	Test Type	Result	Remarks
IEC 61000-4-2:2008 ED.2.0	Electrostatic discharge immunity test	PASS	Meets the requirements of Performance Criterion B
IEC 61000-4-3:2010 ED.3.2	Radiated, radio-frequency, electromagnetic field immunity test	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-4:2012 ED.3.0	Electrical fast transient / burst immunity test.	PASS	Meets the requirements of Performance Criterion B
IEC 61000-4-5:2005 ED.2.0	Surge immunity test	PASS	Meets the requirements of Performance Criterion B
IEC 61000-4-6:2008 ED.3.0	Immunity to conducted disturbances, induced by radio-frequency fields	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-8:2009 ED.2.0	Power frequency magnetic field immunity test.	PASS	Meets the requirements of Performance Criterion A
IEC 61000-4-11:2004 ED.2.0	Voltage dips and short interruptions immunity tests	PASS	Meets the requirements of Voltage Dips: i) >95% reduction - Performance Criterion A i) i30% reduction – Performance Criterion A Voltage Interruptions: i) >95% reduction – Performance Criterion B